FORM 1449: PE CONFORMATION DISCLOSURE STATEMENT	Docket Number: 50019.0272US01	Application Number: 10/786,846
IN AN APPLICATION	Applicant: Qiang Luo	
(Use several sheets if necessary)	Filing Date: 2/25/2004	Group Art Unit: Not Yet Assigned

CAT & THE								
U.S. PATENT DOCUMENTS								
EXAMINER INITIAL	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS		DATE OPRIATE	
(Mh)	5,841,158	11/24/1998	Merrill	257	233			
mo	5/841,176	11/24/1998	Merrill	257	446			
7,				,				
		_						
						-		
	•		· · · · · · · · · · · · · · · · · · ·			-		
	•					-		
		<u>. </u>						
*						· ,		
	<u> </u>	FOR	EIGN PATENT DOCUME	ENTS	<u> </u>			
	DOCUMENTNO. DATE COUNTRY CLASS SUBCLASS TRA				TRANS	NSLATION		
						YES	NO	
¥1 .	OTHER I	DOCUMENTS	(Including Author, Title, Da	ate, Pertinent I	Pages, Etc.)			
Ams	Scott R. Stiffler, Jerry B. Lasky, Charles W. Koburger and Wayne S. Berry; Oxidation-Induced Defect Generation in Advanced DRAM Structures; May 1990, Volume 37, Number 5, A Publication of the IEEE Electron Devices Society; pgs. 1253-1258							
Jus	Yukio Takano and Hirotsugu Kozuka; Dislocation Generation due to Stress Induced by Oxidation in Si Grooves; Japanese Journal of Applied Physics Volume 22 (1983) Supplement 22-1; PGS. 553-556; Proceedings of the 14 th Conference (1982 International) on Solid State Devices, Tokyo 1982							
Muis	Hsiu-Yu Cl September	Hsiu-Yu Cheng and Ya-Chin King; An Ultra-Low Dark Current CMOS Image Sensor Cell Using n+ Ring Reset; September 2002, Volume 23, Number 9, A Publication of the IEEE Electron Devices Society; pgs. 538-540						
Mus	Ikuko Inoue, Nagataka Tanaka, Hirofumi Yamashita, Tetsuya Yamaguchi, Hiroaki Ishiwata and Hisanori Ihara; Low-Leakage-Current and Low-Operating-Voltage Buried Photodiode for a CMOS Image; January 2003, Volume 50, Number 1, 2003 IEEE; pgs. 43-47							

23552
PATENT TRADEMARK OFFICE

	<u> </u>				
EXAMINER	Chrusa	With the	DATE CONSIDERED	12/27/05	

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form for next communication to the Applicant.

<i>)</i>		010	<u> </u>			Shees 1 of 1	
FORM EKC-14	12	E 3 1 7005 &	Ally: Docker No. 89044PCW Customer No. 01333		-	Serial No. 10/786,846	
or 3 mo		only with Rule 97(E)	Applicant: Qiang Luo				
			Filing Date 25 February 2004			Graw 2811	
		U.S. PA	TENT DOCUMENTS		<u> </u>		
Examiner Initial*	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
1.m	6,534,335 B1	03-18-2003	Rhodes et al.	T —	<u> </u>		
ms	2001/0017382 A1	08-30-2001	Rhodes et al.	*			
mi	6,495,391 B1	12-17-2002	Chan				
		FOREIGN	PATENT DOCUMENTS				
Examiner Initial*	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO	
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER CAUSE AN ACCONSIDERED 12/27/05							
*ENAMINER: tythal if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance							